

Form PTO-1449 U.S. Department of Commerce (Rev. 8-83) Patent and Trademark Office				Attorney Docket No. 0756-1653		Serial No. 08/818.884	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				Applicant: Shunpei YAMAZAKI, et al.			
				Filing Date: September 5, 2000		Group: 2871	
FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation Yes No	
DN	0 161 555*	11/1985	EP	—	—		
	0 321 073*	06/1989	EP	—	—		
	0 337 457	10/18/89	EP	—	—		
	49-77537*	07/1974	JP	—	—		X
	55-011329*	01/1980	JP	—	—	Full	
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DN	59-072182*	04/1984	JP	—	—	Full	
Examiner <u>DNQUEN</u>			Date Considered <u>9/18/04</u>				
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(Rev. 8-83) Patent and Trademark Office

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DN	59-072128*	04/1984	JP	-	-	Full
	59-115574*	07/1984	JP	-	-	Full
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Form PTO-1449 U.S. Department of Commerce (Rev. 8-83) Patent and Trademark Office				Attorney Docket No. 0756-2230		Serial No. 08/818,884	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				Applicant: Shunpei YAMAZAKI, et al.			
				Filing Date: September 5, 2000		Group: 2871	
FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation Yes No	
DN	1-130131*	05/1989	JP	-	-	Abstract	
	1-156725*	06/1989	JP	-	-	Full	
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DN	2-234134*	09/1990	JP	-	-	Full	
Examiner <u>DNHUYEN</u>			Date Considered <u>9/18/04</u>				
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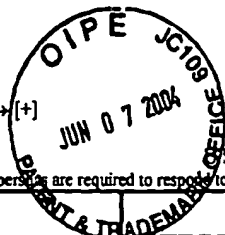
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INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				Applicant: Shumpei YAMAZAKI			
				Filing Date: September 5, 2000		Group: 2871	
FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation Yes No	
DN	3-290924*	12/1991	JP	-	-	Abstract	
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Examiner <u>DNUNEN</u>				Date Considered <u>09/18/04</u>			
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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)			
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Substitute for form 1449A/PTO				Complete If Known	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(use as many sheets as necessary)</i>				Application Number	08/818,884
				Filing Date	March 17, 1997
				First Named Inventor	Shunpei YAMAZAKI et al.
				Group Art Unit	2871
				Examiner Name	D. Nguyen
Sheet	1	of	1	Attorney Docket Number	0756-1653

U.S. PATENT DOCUMENTS						
Examiner Initials ¹	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code ² (if known)			
DN		3,820,108		Luce	06/25/1974	
DN		4,409,724		Tasch, Jr. et al.	10/18/1983	
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Examiner Initials ¹	Cite No. ¹	Foreign Patent Document			Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Office ³	Number ⁴	Kind Code ² (if known)			
DN		EP	0 553 775		—	08/04/1993	—
DN		EP	0 554 063		—	08/04/1993	—
DN		JP	05-249495		—	09/28/1993	—
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DN		JP	06-250214		—	09/09/1994	—

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS			
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INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)				Application Number	08/818,884
				Filing Date	March 17, 1997
				First Named Inventor	Shunpei YAMAZAKI et al.
				Group Art Unit	2871
				Examiner Name	D. Nguyen
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DN		JP	63-208896		—	08/30/1988	—	Full

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